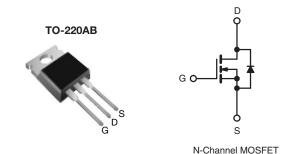


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	200				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 1.5				
Q _g (Max.) (nC)	8.2				
Q _{gs} (nC)	1.8				
Q _{gd} (nC)	4.5				
Configuration	Single				



FEATURES

- · Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling

DESCRIPTION

- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220AB package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220AB contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220AB
Load (Dh) froe	IRF610PbF
Lead (Pb)-free	SiHF610-E3
SnPb	IRF610
SIFD	SiHF610

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	200		
Gate-Source Voltage			V_{GS}	± 20	V	
Continuous Drain Current	T _C = 25 °C		3.3			
Continuous Drain Current	V _{GS} at 10 V	$T_C = 25 \degree C$ $T_C = 100 \degree C$	ID	2.1	Α	
Pulsed Drain Current ^a			I _{DM}	10		
Linear Derating Factor				0.29	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	64	mJ	
Repetitive Avalanche Current ^a			I _{AR}	3.3	Α	
Repetitive Avalanche Energy ^a			E _{AR}	3.6	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	36	W	
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d	7	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \, ^{\circ}\text{C}$, $L = 8.8 \, \text{mH}$, $R_g = 25 \, \Omega$, $I_{AS} = 3.3 \, \text{A}$ (see fig. 12).
- c. $I_{SD} \le 3.3$ A, $dI/dt \le 70$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	62			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.5			

SPECIFICATIONS ($T_J = 25 ^{\circ}C$, u		100 110104,				ı	_
PARAMETER	SYMBOL	TEST	TEST CONDITIONS			MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I _D = 1 mA	-	0.30	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V$	I_{GS} , $I_{D} = 250 \mu A$	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	$S = \pm 20 \text{ V}$	1	-	± 100	nA
Zero Gate Voltage Drain Current	1	V _{DS} = 2	V _{DS} = 200 V, V _{GS} = 0 V		-	25	
Zelo Gate Voltage Drain Guirent	I _{DSS}	$V_{DS} = 160 \text{ V}, \text{ V}$	$I_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$	1	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.0 A ^b	-	-	1.5	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 5	0 V, I _D = 2.0 A ^b	0.8	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V	_{GS} = 0 V,	-	140	-	
Output Capacitance	C _{oss}	V	$_{OS} = 25 \text{ V},$	-	53	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	15	-	
Total Gate Charge	Qg		I _D = 3.3 A, V _{DS} = 160 V, see fig. 6 and 13 ^b	-	-	8.2	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	1.8	
Gate-Drain Charge	Q _{gd}		See fig. 6 dila 16	-	-	4.5	
Turn-On Delay Time	t _{d(on)}	$V_{DD}=100~\text{V, I}_D=3.3~\text{A,}$ $R_g=24~\Omega,~R_D=30~\Omega,~\text{see fig. }10^{\text{b}}$		-	8.2	-	- ns
Rise Time	t _r			-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	14	-	
Fall Time	t _f			-	8.9	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.3	^
Pulsed Diode Forward Current ^a	I _{SM}			-	-	10	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.3 A, V _{GS} = 0 V ^b		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 3.3 \text{A}, \text{dI/dt} = 100 \text{A/µs}^{\text{b}}$		-	150	310	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.60	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				1.5)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

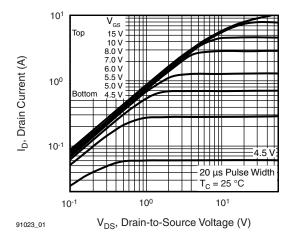


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

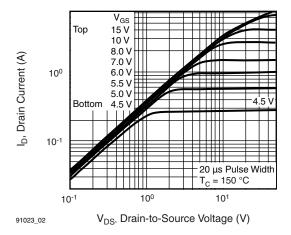


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

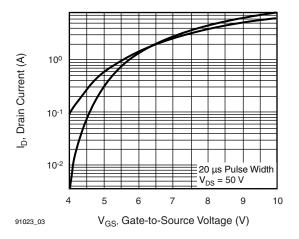


Fig. 3 - Typical Transfer Characteristics

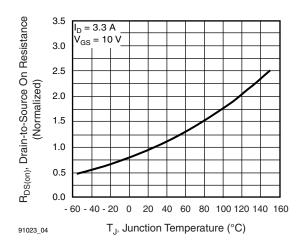


Fig. 4 - Normalized On-Resistance vs. Temperature



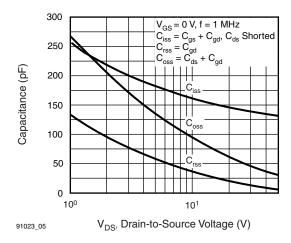


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

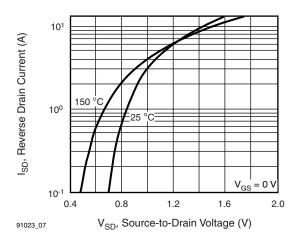


Fig. 7 - Typical Source-Drain Diode Forward Voltage

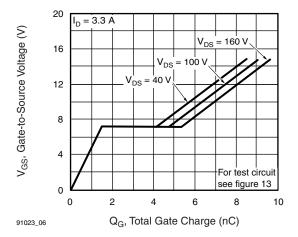


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

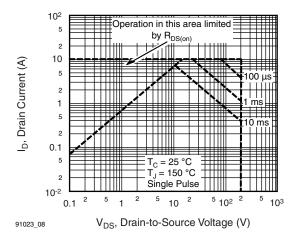
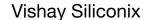


Fig. 8 - Maximum Safe Operating Area





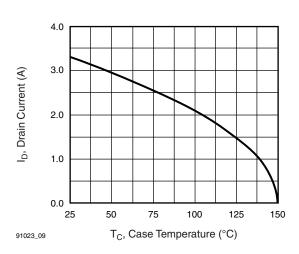


Fig. 9 - Maximum Drain Current vs. Case Temperature

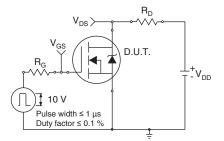


Fig. 10a - Switching Time Test Circuit

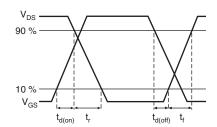


Fig. 10b - Switching Time Waveforms

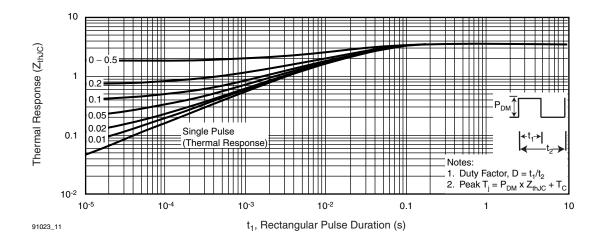


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



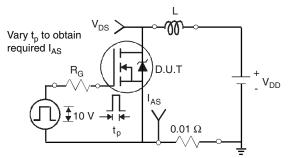


Fig. 12a - Unclamped Inductive Test Circuit

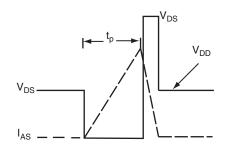


Fig. 12b - Unclamped Inductive Waveforms

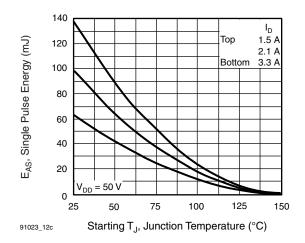


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

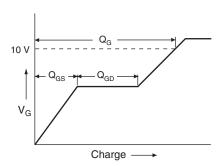


Fig. 13a - Basic Gate Charge Waveform

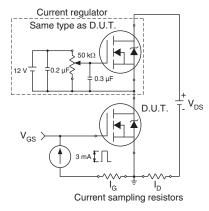
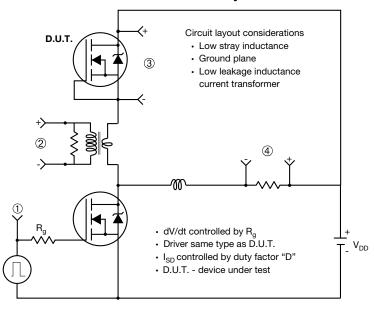


Fig. 13b - Gate Charge Test Circuit





Peak Diode Recovery dV/dt Test Circuit



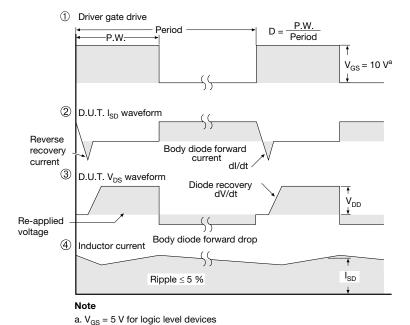


Fig. 14 - For N-Channel

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TO-220-1



DIM.	MILLIM	IETERS	INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.24	4.65	0.167	0.183		
b	0.69	1.02	0.027	0.040		
b(1)	1.14	1.78	0.045	0.070		
С	0.36	0.61	0.014	0.024		
D	14.33	15.85	0.564	0.624		
Е	9.96	10.52	0.392	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.10	6.71	0.240	0.264		
J(1)	2.41	2.92	0.095	0.115		
L	13.36	14.40	0.526	0.567		
L(1)	3.33	4.04	0.131	0.159		
ØР	3.53	3.94	0.139	0.155		
Q	2.54	3.00	0.100	0.118		
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031						

Note

 M* = 0.052 inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



Revison: 14-Dec-15 1 Document Number: 66542



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